T-46-07-05

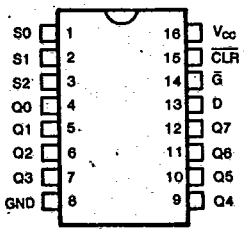
KS54HCTLS/KS74HCTLS 259

8-Bit Addressable Latches

FEATURES

- 8-Bit parallel-out storage register performs serial-to-parallel conversion with storage
- Asynchronous parallel clear
- Active high decoder
- Enable/Disable input simplifies expansion
- Expandable for N-bit applications
- Four distinct functional modes
- Function, pin-out, speed and drive compatibility with 54/74LS logic family
- Low power consumption characteristic of CMOS
- High-Drive-Current outputs: I_{OL} = 8 mA @ V_{OL} = 0.5V
- Inputs and outputs interface directly with TTL, NMOS and CMOS devices
- Wide operating voltage range: 4.5V to 5.5V
- Characterized for operation over industrial and military temperature ranges:
  KS74HCTLS: −40°C to +85°C
  KS54HCTLS: −55°C to +125°C
- Package options include plastic "small outline" packages, standard plastic and ceramic 300-mil DIPs

PIN CONFIGURATION



DESCRIPTION

The '259 is a high-speed addressable latch designed for general purpose storage applications in digital systems. It can be used for implementing working registers, serial-holding registers and active-high decoders or demultiplexers.

The '259 has four distinct modes of operation that are selected via the clear ($\overline{CLR}$) and enable ($\overline{G}$) inputs: 1) addressable latch; 2) memory; 3) active-high eight-channel demultiplexer; and 4) clear.

In the addressable latch mode, data on the data input (D) is written into the addressed latch. In this mode, data will be written into the addressed latch with all non-addressed latches remaining in their previous states.

In the memory mode, all latches remain in their previous state and are unaffected by the data of address inputs.

In the demultiplexing mode, addressed outputs will follow the state of the D input and all other outputs will remain low.

In the clear mode, all outputs are low and unaffected by the address and data inputs.

These devices provide speeds and drive capability equivalent to their LSTTL counterparts and yet maintain CMOS power levels. The input and output voltage levels allow direct interface with TTL, NMOS and CMOS devices without any external components.

All inputs and outputs are protected from damage due to static discharge by internal diode clamps to V_{CC} and ground.

FUNCTION TABLE

Inputs		Output of Addressed Latch	Each Other Output	Function
$\overline{CLR}$	$\overline{G}$			
H	L	D	Q_{i0}	Addressable Latch
H	H	Q_{i0}	Q_{i0}	Memory
L	L	D	L	8-Line Demultiplexer
L	H	L	L	Clear

D = the level at the data input.
Q_{i0} = the level of Q_{i0} (i = Q, 1, ... 7, as appropriate) before the indicated steady-state input conditions were established.

LATCH SELECTION TABLE

Select Inputs			Latch Addressed
S2	S1	S0	
L	L	L	0
L	L	H	1
L	H	L	2
L	H	H	3
H	L	L	4
H	L	H	5
H	H	L	6
H	H	H	7

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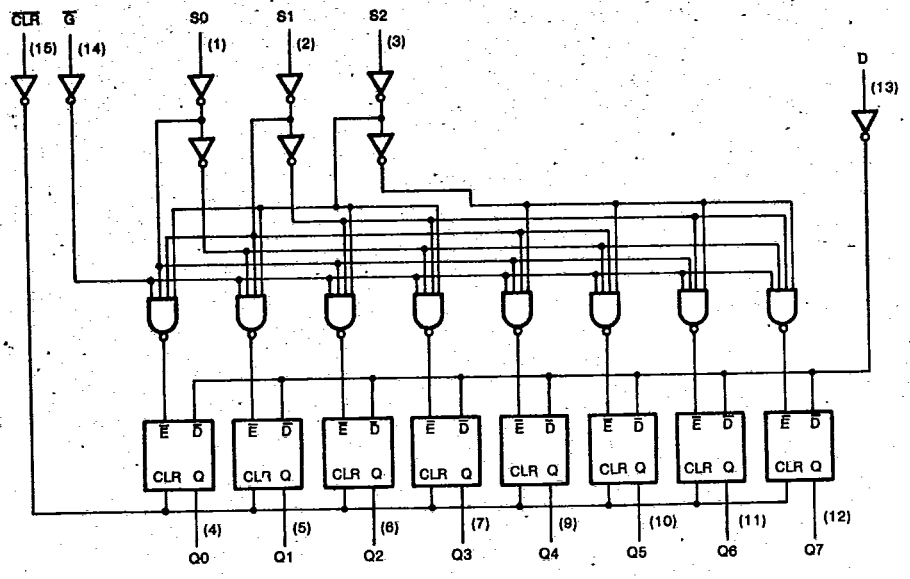
LOGIC DIAGRAM



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Absolute Maximum Ratings*

Supply Voltage Range V_{CC}, ... −0.5V to +7V
DC Input Diode Current, I_{IK}
(V_I < −0.5V or V_I > V_{CC} +0.5V) . . . . . ±20 mA
DC Output Diode Current, I_{OK}
(V_O < −0.5V or V_O > V_{CC} +0.5V) . . . . ±20 mA
Continuous Output Current Per Pin, I_O
(−0.5V < V_O < V_{CC} +0.5V) . . . . . ±35 mA
Continuous Current Through
V_{CC} or GND pins . . . . . ±125 mA
Storage Temperature Range, T_{stg} . . . −65°C to +150°C
Power Dissipation Per Package, P_d† . . . . . 500 mW

* Absolute Maximum Ratings are those values beyond which permanent damage to the device may occur. These are stress ratings only and functional operation of the device at or beyond them is not implied. Long exposure to these conditions may affect device reliability.

Power Dissipation temperature derating:
Plastic Package (N): −12mW/°C from 65°C to 85°C
Ceramic Package (J): −12mW/°C from 100°C to 125°C

Recommended Operating Conditions

Supply Voltage, V_{CC} . . . . . 4.5V to 5.5V
DC Input & Output Voltages*, V_{IN}, V_{OUT} . . . 0V to V_{CC}
Operating Temperature
Range KS74HCTLS: −40°C to +85°C
KS54HCTLS: −55°C to +125°C
Input Rise & Fall Times, t_r, t_f . . . . . Max 500 ns

* Unused inputs must always be tied to an appropriate logic voltage level (either V_{CC} or GND)

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DC ELECTRICAL CHARACTERISTICS (V_{CC}=5V±10% Unless Otherwise Specified)

Characteristic	Symbol	Test Conditions	T_a=25°C	KS74HCTLS T_a=−40°C to +85°C	KS54HCTLS T_a=−55°C to +125°C	Unit
			Typ	Guaranteed Limits		
Minimum High-Level Input Voltage	V_{IH}			2.0	2.0	2.0	V
Maximum Low-Level Input Voltage	V_{IL}			0.8	0.8	0.8	V
Minimum High-Level Output Voltage	V_{OH}	V_{IN}=V_{IH} or V_{IL} I_O=−20μA I_O=−4mA	 V_{CC} 4.2	 V_{CC} −0.1 3.98	 V_{CC} −0.1 3.84	 V_{CC} −0.1 3.7	V
Maximum Low-Level Output Voltage	V_{OL}	V_{IN}=V_{IH} or V_{IL} I_O=20μA I_O=4mA I_O=8mA	 0 •	 0.1 0.26 0.39	 0.1 0.33 0.5	 0.1 0.4	V
Maximum Input Current	I_{IN}	V_{IN}=V_{CC} or GND		±0.1	±1.0	±1.0	μA
Maximum Quiescent Supply Current	I_{CC}	V_{IN}=V_{CC} or GND I_{OUT}=0μA		8.0	80.0	160.0	μA
Additional Worst Case Supply Current	ΔI_{CC}	per input pin V_I=2.4V other inputs: at V_{CC} or GND I_{OUT}=0μA		2.7	2.9	3.0	mA

AC ELECTRICAL CHARACTERISTICS (Input t_r, t_f≤6 ns), HCTLS259

Characteristic		Symbol	Conditions†	T_a=25°C V_{CC}=5.0V		KS74HCTLS T_a=−40°C to +85°C V_{CC}=5.0V±10%	KS54HCTLS T_a=−55°C to +125°C V_{CC}=5.0V± 10%	Unit
				Typ	Guaranteed Limits			
Maximum Propagation Delay $\overline{CLR}$ to any Q		t_{PHL}	C_L=50pF	22	30	37	45	ns
Maximum Propagation Delay, Data to Any Q		t_{PLH}		20	27	34	41	ns
		t_{PHL}		20	27	34	41	
Maximum Propagation Delay, Address to any Q		t_{PLH}		26	34	43	51	ns
		t_{PHL}		26	34	43	51	
Maximum Propagation Delay, $\overline{G}$ to any Q		t_{PLH}		22	30	37	45	ns
		t_{PHL}		22	30	37	45	
Minimum Pulse Width	$\overline{CLR}$ LOW	t_w		8	10	13	15	ns
	$\overline{G}$ Low			8	10	13	15	
Minimum Setup Time, Data or Address before $\overline{G}$↑		t_{su}		8	10	13	15	ns
Minimum Hold Time, Data or Address before $\overline{G}$↑		t_h		−3	0	0	0	ns
Maximum Input Capacitance		C_{IN}		5				pF
Power Dissipation Capacitance*		C_{PD}		80				pF

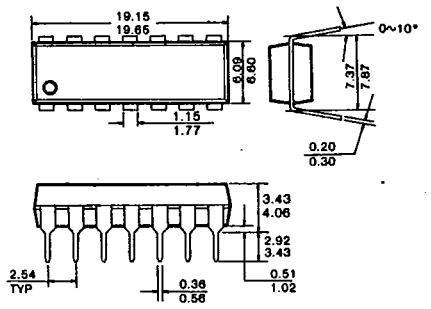
* C_{PD} determines the no-load dynamic power dissipation: P_D=C_{PD} V_{CC}^2 f + I_{CC} V_{CC}.
† For AC switching test circuits and timing waveforms see section 2.

PACKAGE DIMENSIONS

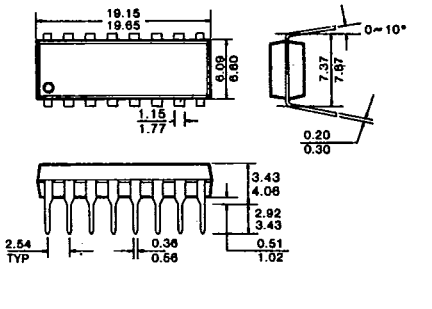
T-90-20

1. PLASTIC PACKAGES

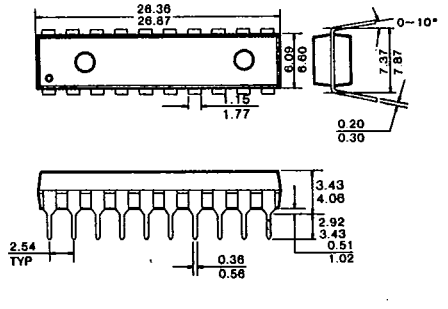
14-Pin Plastic DIP **Units: mm**



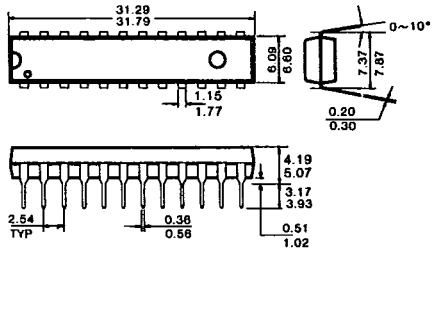
16-Pin Plastic DIP **Units: mm**



20-Pin Plastic DIP **Units: mm**



24-Pin Plastic DIP **Units: mm**



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PACKAGE DIMENSIONS

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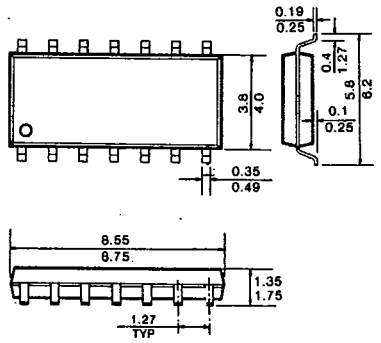
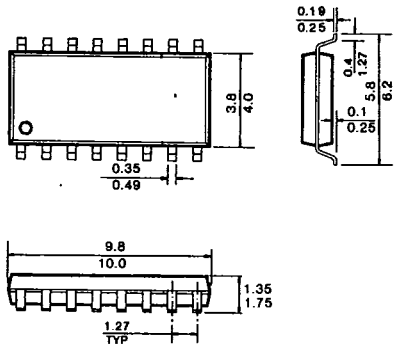
14-Pin SOP

Unit: mm



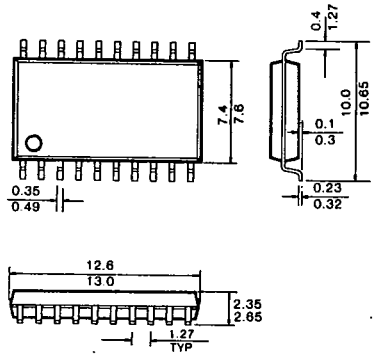
16-Pin SOP

Unit: mm



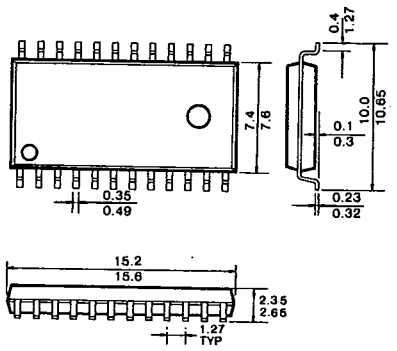
20-Pin SOP

Unit: mm



24-Pin SOP

Unit: mm



PACKAGE DIMENSIONS

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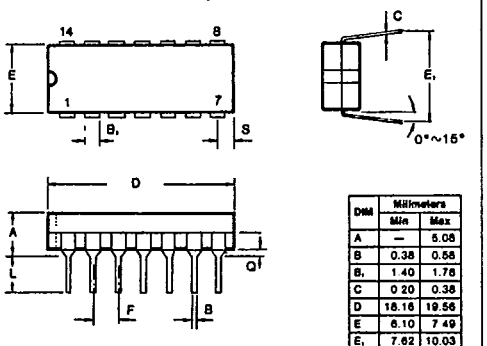
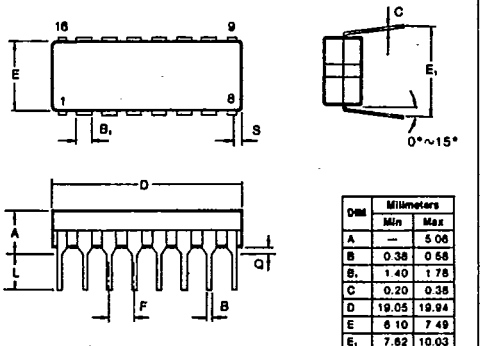
2. CERAMIC PACKAGES

14-Pin Ceramic DIP Units: mm



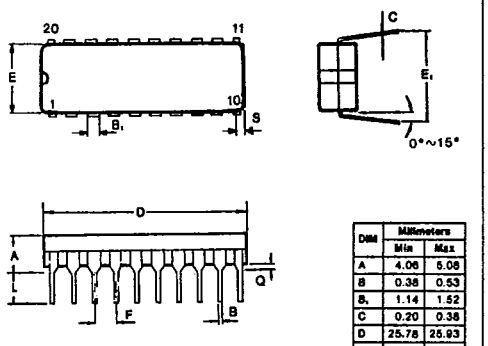
DIM	Millimeters	
	Min	Max
A	—	5.08
B	0.38	0.58
B1	1.40	1.78
C	0.20	0.38
D	18.16	19.56
E	6.10	7.49
E1	7.62	10.03
F	2.54	
L	3.18	4.19
Q	0.51	1.02
S	1.91	2.29

16-Pin Ceramic DIP Units: mm



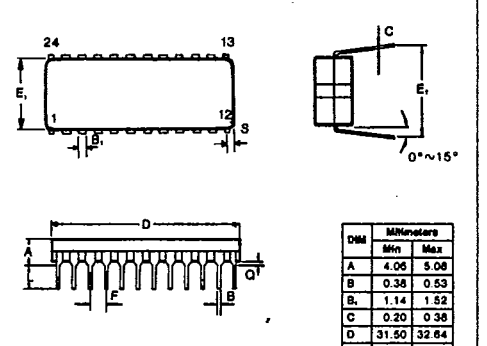
DIM	Millimeters	
	Min	Max
A	—	5.08
B	0.38	0.58
B1	1.40	1.78
C	0.20	0.38
D	19.05	19.94
E	6.10	7.49
E1	7.62	10.03
F	2.54	
L	3.18	4.19
Q	0.51	1.02
S	0.51	1.14

20-Pin Ceramic DIP Units: mm



DIM	Millimeters	
	Min	Max
A	4.06	5.08
B	0.38	0.53
B1	1.14	1.52
C	0.20	0.38
D	25.78	25.93
E	6.10	6.60
E1	7.77	7.98
F	2.54	
L	3.73	4.01
Q	0.38	0.89
S	0.51	1.14

24-Pin Ceramic DIP Units: mm



DIM	Millimeters	
	Min	Max
A	4.06	5.08
B	0.38	0.53
B1	1.14	1.52
C	0.20	0.38
D	31.50	32.64
E	7.24	7.75
E1	7.77	7.98
F	2.54	
L	3.73	4.01
Q	0.508	1.778
S	1.65	1.93

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